

## N-Channel 200 V (D-S) MOSFET

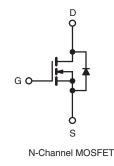
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	200				
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 10 V	0.265			
Q <sub>g</sub> (Max.) (nC)	16				
Q <sub>gs</sub> (nC)	5				
Q <sub>gd</sub> (nC)	8				
Configuration	Single				

#### **FEATURES**

- · Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- · Lead (Pb)-free Available







<b>ABSOLUTE MAXIMUM RATINGS</b> T	<sub>C</sub> = 25 °C, unless otherv	vise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V <sub>DS</sub>	200	v	
Gate-Source Voltage		V <sub>GS</sub>	± 20		
Continuous Drain Current	$V_{GS}$ at 10 V $T_C = 25 \degree C$		10		
	$V_{GS}$ at 10 V $T_C = 100 ^{\circ}C$		6.5	A	
Pulsed Drain Currenta	I <sub>DM</sub>	32	1		
Linear Derating Factor		0.24	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>		E <sub>AS</sub>	36	mJ	
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>	7.2	A		
Repetitive Avalanche Energy <sup>a</sup>	E <sub>AR</sub>	3.7	mJ		
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	PD	P <sub>D</sub> 37		
Peak Diode Recovery dV/dtc	dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-52 OF MIS SCIEW		1.1	N ⋅ m	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 1.0 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 7.2 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 9.2 \text{ A}$ , dl/dt  $\le 110 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \text{ °C}$ .

d. 1.6 mm from case.



PARAMETER	SYMBOL	ТҮР	P	MAX.			UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65							
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 4.1				°C/W			
<b>SPECIFICATIONS</b> $T_J = 25 \degree C$ ,	unless other	wise noted							
PARAMETER	SYMBOL	TEST CONDITIONS			MIN.	TYP.	MAX.	UNI	
Static						1	1	1	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> -	= 0 V, I <sub>D</sub> = 250	μA	200	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	ce to 25 °C, I <sub>D</sub>	= 1 mA	-	0.13	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>		= V <sub>GS</sub> , I <sub>D</sub> = 250		2.0	-	4.0	v	
Gate-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 20 \text{ V}$			-	± 100	nA	
	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V	0 V	-	-	25	+			
Zero Gate Voltage Drain Current		V <sub>DS</sub> =160 V	, V <sub>GS</sub> = 0 V, T	ı = 150 °C	-	-	250	μΑ	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4	4.3 A <sup>b</sup>	-	0.265	-	Ω	
Forward Transconductance	<b>g</b> <sub>fs</sub>	V <sub>DS</sub> =	= 50 V, I <sub>D</sub> = 4.3	3 A <sup>b</sup>	2.3	-	-	S	
Dynamic		1							
Input Capacitance	Ciss	$V_{cc} = 0 V_{cc}$			-	560	-	pF	
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1.0 MHz, see fig. 5		-	260	-			
Reverse Transfer Capacitance	C <sub>rss</sub>			-	110	-			
Drain to Sink Capacitance	С		f = 1.0 MHz		-	12	-	1	
Total Gate Charge	Qg				-	-	16	1	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V} \qquad \begin{array}{c} I_{D} = 9.2 \text{ A},  V_{DS} = 80 \text{ V}, \\ \text{see fig. 6 and } 13^{b} \end{array}$		-	-	4.4	nC	
Gate-Drain Charge	Q <sub>gd</sub>				-	-	7.7		
Turn-On Delay Time	t <sub>d(on)</sub>	$\label{eq:V_DD} \begin{array}{l} V_{DD} \ = \ 100 \ \text{V}, \ \text{I}_{D} = \ 9.2 \ \text{A}, \\ R_{G} \ = \ 18 \ \Omega, \ \text{R}_{D} = \ 5.2 \ \Omega, \\ \text{see fig. 10}^{\text{b}} \end{array}$		-	8.8	-	1		
Rise Time	t <sub>r</sub>				-	30	-	1	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	19	-	ns		
Fall Time	t <sub>f</sub>			-	20	-			
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-			
Internal Source Inductance	Ls			-	7.5	-	- nH		
Drain-Source Body Diode Characteristic	s				•	•			
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	10	-	- A		
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	32	-			
Body Diode Voltage	$V_{SD}$	$T_{J} = 25 \ ^{\circ}C, \ I_{S} = 7.2 \ A, \ V_{GS} = 0 \ V^{b}$		-	-	2.5	V		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \ ^{\circ}C, I_F = 9.2 \text{ A}, dI/dt = 100 \text{ A}/\mu \text{s}^{b}$		-	130	260	ns		
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.65	1.3	μC		
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	urn-on time is r	negligible (turn	-on is dor	ninated by	y L <sub>S</sub> and I	_D)	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

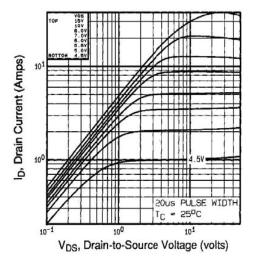


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

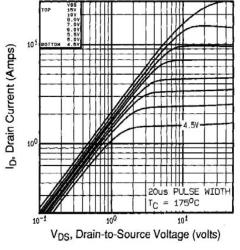


Fig. 2 - Typical Output Characteristics,  $T_C$  = 175 °C

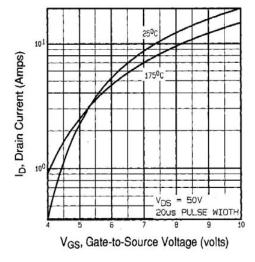


Fig. 3 - Typical Transfer Characteristics

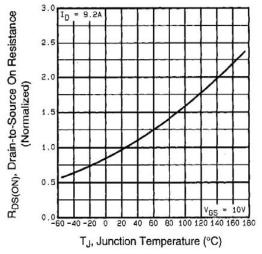


Fig. 4 - Normalized On-Resistance vs. Temperature



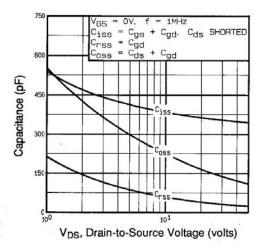


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

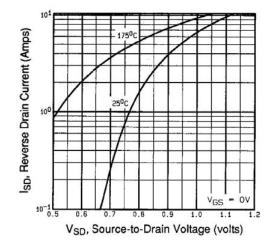


Fig. 7 - Typical Source-Drain Diode Forward Voltage

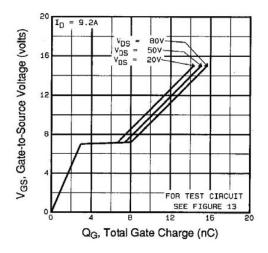


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

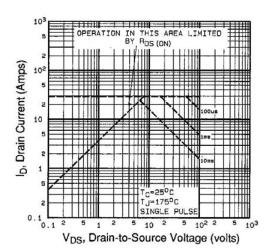


Fig. 5 - Fig. 8 - Maximum Safe Operating Area



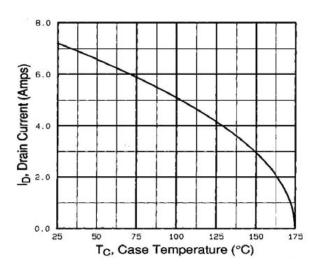


Fig. 9 - Maximum Drain Current vs. Case Temperature

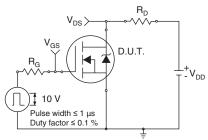


Fig. 10a - Switching Time Test Circuit

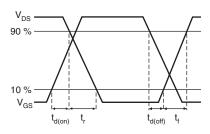
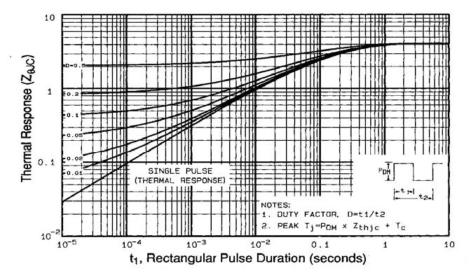


Fig. 10b - Switching Time Waveforms





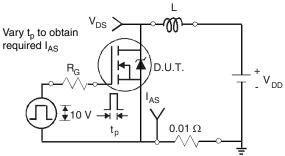


Fig. 12a - Unclamped Inductive Test Circuit

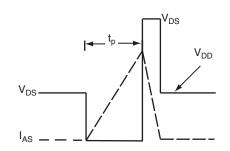
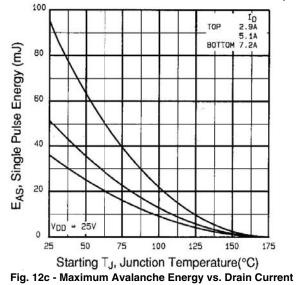


Fig. 12b - Unclamped Inductive Waveforms





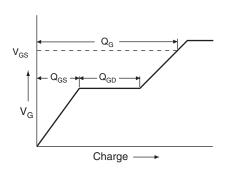


Fig. 13a - Basic Gate Charge Waveform

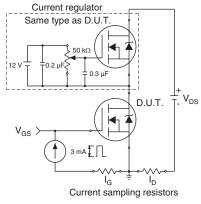
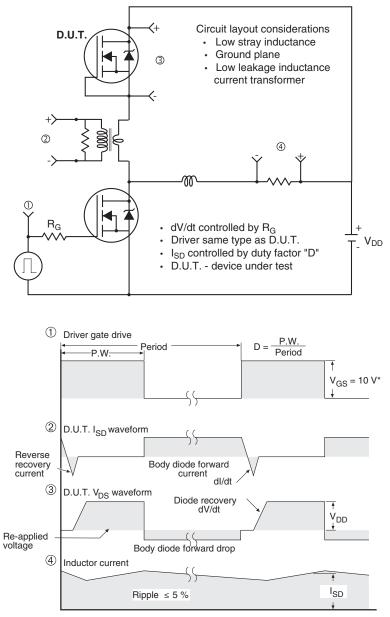


Fig. 13b - Gate Charge Test Circuit





### Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS} = 5$  V for logic level devices

Fig. 14 - For N-Channel



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